



Amkor ATP3 (Philippines) additional source for STM32F429 & F439 in TFBGA 13x13 package

MMS - Microcontrollers Division (MCD)

Dear Customer,

Committed to serving our customers, our teams operate with the constant objective to improve customer service through increased capacity and double-sourcing.

What are the changes?

The change is the qualification of Amkor ATP3 (Philippines) for STM32F429x and STM32F439 x devices in TFBGA 13x13 package, as an additional assembly site.

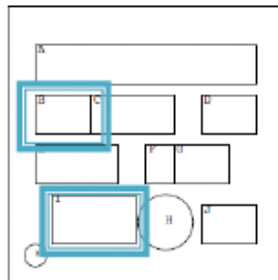
New Bill Of Material is described below:

Bill OfMaterial	Current	Added
Assembly site	ST Muar (Malaysia)	Amkor ATP3 (Philippines)
Mold compound	HITACHI GE-100 LF1-2	HITACHI GE100LFCS
Glue	ABLESTIK 2100 A	ABLESTIK 2300
Solder balls	SACN306 D0.35mm	SAC105 D0.35mm
Die thickness after backlap	235µm	180µm

How can the change be seen?

Traceability of the change is ensured by ST internal tools.

The marking composition indicated on the products is changing:



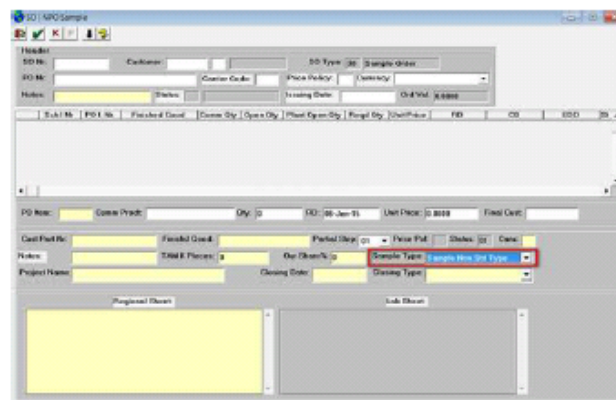
B : Assy plant
changes from 99 to 7B

I : Country Of Origin
changes from MYS to PHL

How to order samples?

For all sample request linked to this PCN, please:

- request sample through Notice tool.
- place **non standard** sample order using the following field in your system.
- insert "PCN 9019" into the remarks of your order.



We remain available to discuss any concern that you may have regarding this Product Change Notification.

With our sincere regards.

Michel Buffa

Microcontroller Division General Manager

PCN9019- RERMCD1421

RELIABILITY PLAN

3

Qualification Reference: RERMCD1421

Issued on: Jan 26, 2015

Assembly Plant: AMKOR Philippines ATP3

Assembly Line: TFBGA 13x13

Devices: MCD Standard products/ STM32F

Package / Process: 13x13x1.2 (216 balls)

MSL: MSL3

Purpose

Qualification of a new assembly line for TFBGA 13x13 package assembled at ATP3 (Amkor Philippines).

Test Vehicles :

Assembly Line	Package balls count	Device (Partial RawLine Code)	Diffusion Process	Number of Lots
TFBGA 13x13x 1.2	216 balls pitch 0.8mm	STM32F4xx (RM*434)	ST Cr300 M10	1
		STM32F7xx (RM*449)		1
		STM32F4xx (RM*419)		1

QUAL PLAN for PCN9019

4

Package Reliability Trials :

(*) tests performed after preconditioning

Reliability Trial		Test Conditions	Pass Criteria	Unit per Lot	Qual Lot nb
PC	Pre Conditioning: Moisture Sensitivity Jedec Level 3	Bake (125°C / 24 hrs) Soak (30°C / 60% RH / 192 hrs) for Jedec level 3	3 passes MSL3	308	3
	J-STD-020/ JESD22-A113	Convection reflow: 3 passes			
UHASt(*)	UnBiased Highly Accelerated Temperature and Humidity Stress JESD22 A118	130°C, 85%RH, 2 atm	96h	77	3
TC(*)	Thermal Cycling	-65°C, +150°C or equivalent	500Cy	77	3
	JESD22 A104				
THB(*)	Temperature Humidity Bias	85°C, 85% RH- bias	1000h	77	3
	JESD22 A101				
HTSL	High Temperature Storage Life	150°C- no bias	1000h	77	3
	JESD22 A103				
ESD	ESD Charge Device Model	6 discharges on each pin (3 positive + 3 negative) +/-250V	250V	3	All devices
	ANSI/ESDSTM5.3.1				
CA	Construction Analysis including : <ul style="list-style-type: none">package dimensionsSolderabilitySolder ball shearTotal ball shearWire bond pullWire bond shear	ADCS#8046024	No major concern	50	1